



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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pre. amt 9
KDuncan
9/9/02

Applicant: Mani SOMA et al.

Art Unit :

Serial No.: 10/033,188

Examiner :

Filed : October 25, 2001

Title : Clock Skew Measurement Device and Measurement Method

Assistant Commissioner for Patents
Washington, DC 20231

PRELIMINARY AMENDMENT

Dear Sir:

Prior to examination on the merits, please amend the application as follows and consider the included remarks.

IN THE DRAWINGS:

Please find enclosed formal drawings for this application. A separate letter to the official draftsperson is also enclosed.

IN THE SPECIFICATION:

Please amend the specification as follows. Marked-up versions of the amended paragraphs are attached.

In the paragraph beginning on page 9, line 32:

91 Fig. 6B shows exemplary timing jitter sequence $\Delta\phi^k[n]$ of a clock CLK_k to be measured.

In the paragraph beginning on page 10, line 6:

92 Fig. 11 shows an exemplary instantaneous phase $\phi(t)$. The discontinuities at $-\Pi$ and $+\Pi$ are observed.

In the paragraph beginning on page 10, line 8:

93 Fig. 12 shows an unwrapped instantaneous phase $\phi(t)$. The discontinuities are removed.